Apsel3D_TC chip characterization

Alejandro Pérez INFN – Sezione di Pisa



SEZIONE DI PISA

Outline

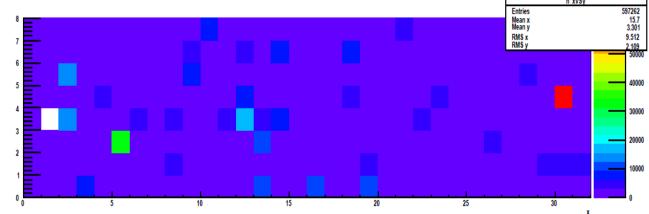
- Noise scans:
 - Chip5
 - Chip6

Differential spectrum with the Fe55 source

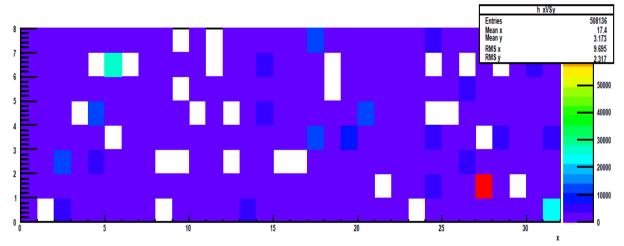
Chip5

Noise scans: Chip5 and Chip6

- Performed noise scans from 1250 up to 1500 DAC (100 steps of 4 DAC)
- Chip5: only one pixel which doesn't turn on

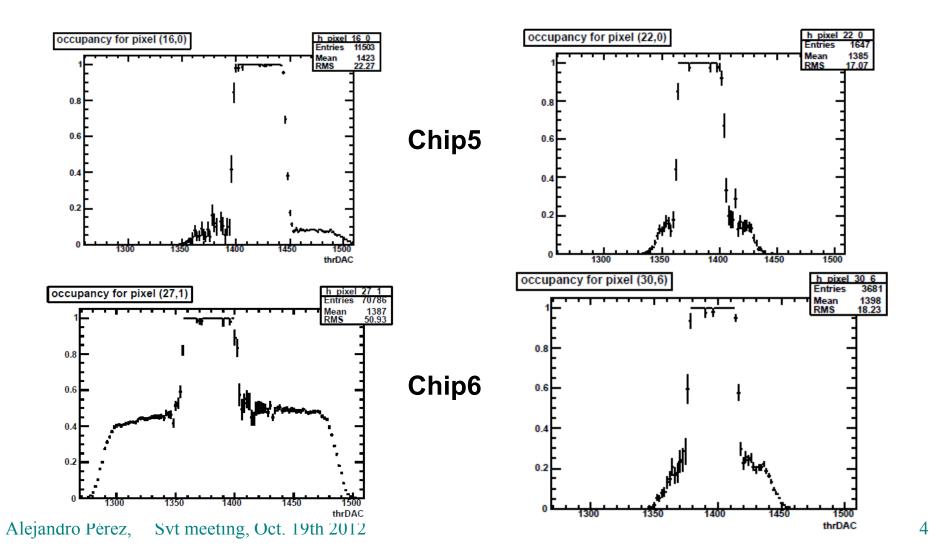


• Chip6: a significant amount of dead pixels ($28 \Rightarrow 11\%$)

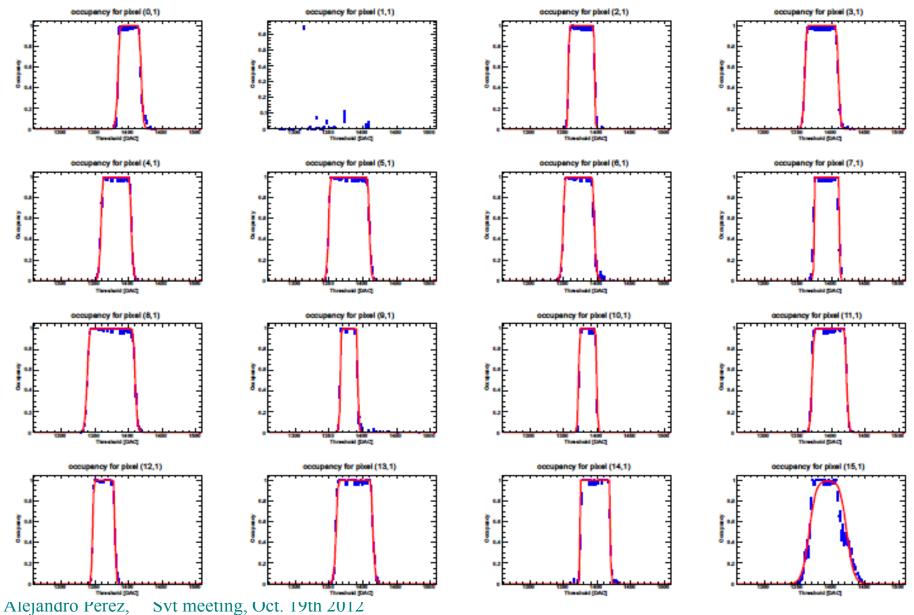


Noise scans: Chip5 and Chip6

- Some pixels for both chips show strange features
- The fit poorly converges in those cases

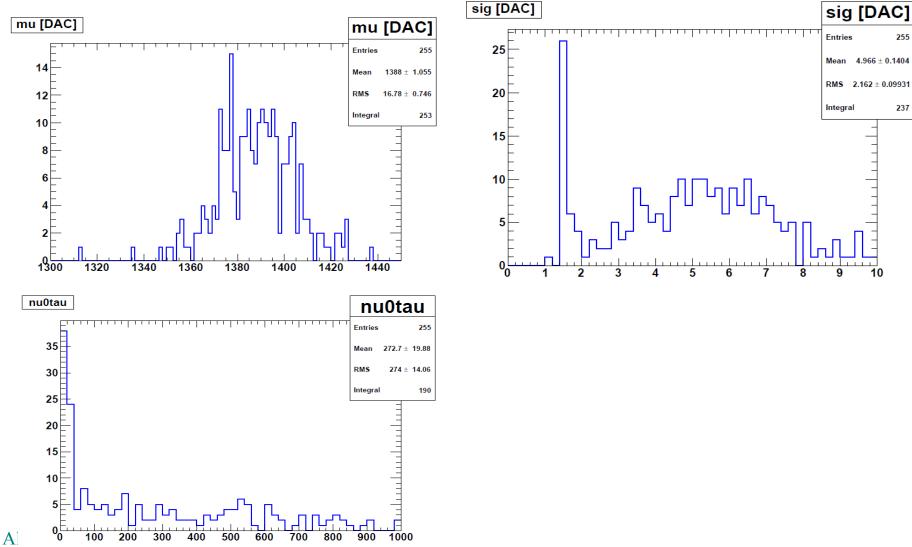


Noise fit: Chip5



Noise scans: Chip5

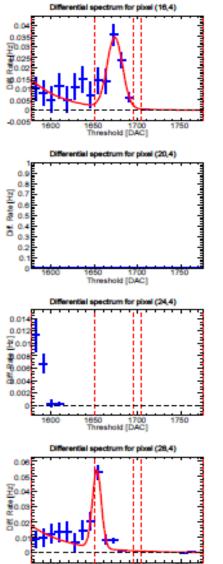
- In some cases the fit doesn't converge properly, still working on it.
- The quantities below need to be interpreted carefully



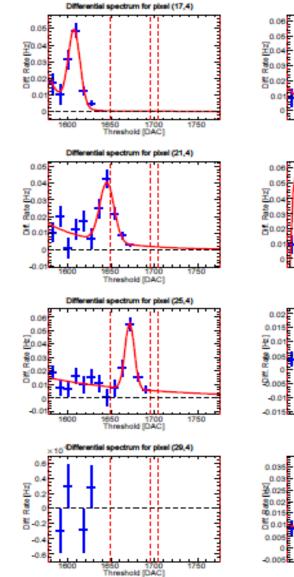
6

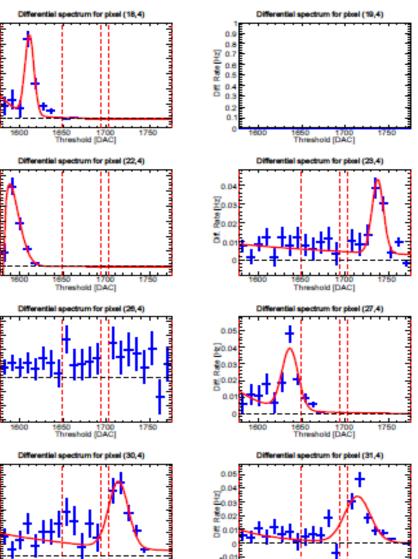
- With the Fe55 source took data varying the threshold, from 1654 to 1780 in steps of 9 (all units in DAC) (three independent runs with non-overlapping intervals) => Integral spectrum
- Out of the integral spectrum calculated the differential spectrum (bin_i+1 bin_i on the integral spectrum)
- Put together the differential spectrum of all the runs
- Tried to look for the Fe55 peak and fit it => Guassian+exponential
- In many cases the peak is not seen and in some other the fit didn't converge
- In this 1st look will only show the results for a selection of pixels that by eye show good behaviour

Example of the fit:



Threshold [DAC]



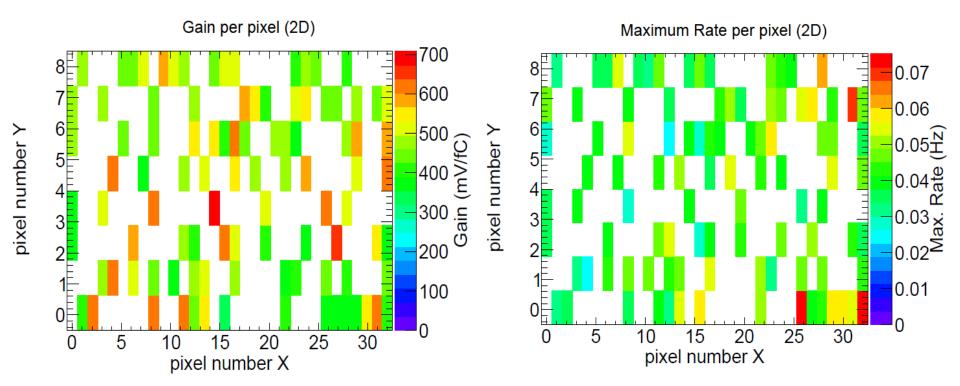


75

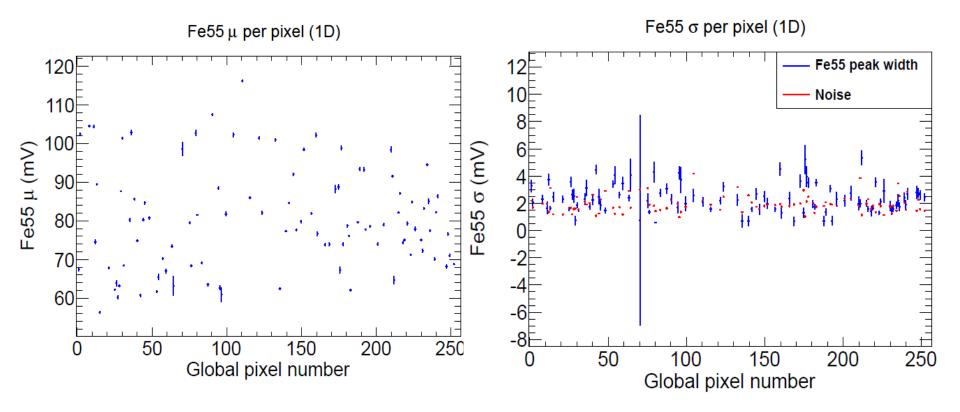
Threshold [DAC]

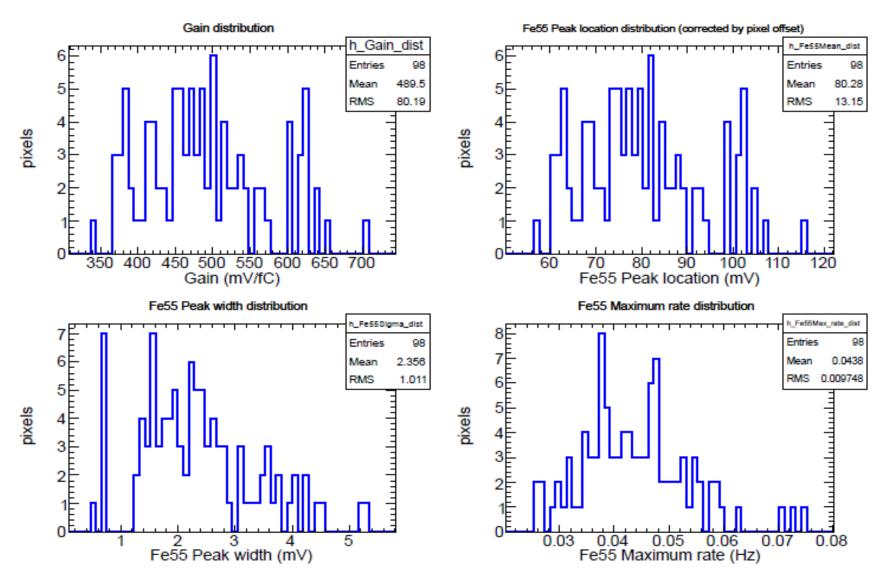
1650 1700 Threshold [DAC]

- Once located the fit, use the noise scan to subtract the pixel baseline and then calculate the gain
- The width of the peak is compared with the amount of noise estimated from the noise scan



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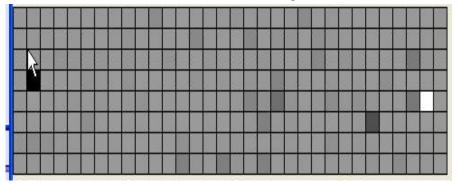


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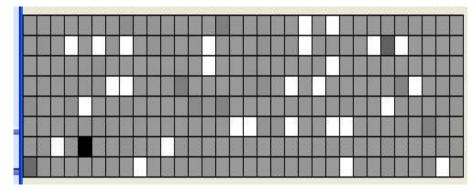


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Noise scan Chip5



Noise scan Chip6



Fe55 at 1520 DAC Thr Chip5



